



New Advances in Optical Imaging and Metrology

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Message from the Guest Editors

Optical imaging and metrology are rapidly developing fields with numerous applications in various domains, including medicine, biology, engineering, and physics. Recently, this field has been making great progress with prevalence of computational optical imaging and metrology. The development tendency of computational imaging and metrology is towards higher resolution and accuracy, faster processing speed, and more sophisticated algorithms for data analysis and interpretation. One key of this trend is the increasing demand for accurate and efficient measurement and imaging techniques for a wide range of applications. Another important trend is the integration of optics with other technologies, such as artificial intelligence (AI), to enable more advanced data processing and analysis. All these developments enable new applications and capabilities that were previously not possible, and will continue to drive innovation in this exciting field.





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Message from the Editor-in-Chief

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